



Sheet 1 of 1

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ASA-481-10SERIAL NO.
10/777,060**LIST OF DOCUMENTS CITED BY APPLICANT**
(Use several sheets if necessary)APPLICANT
N. HASEGAWA et al.FILING DATE
February 13, 2004GROUP
1756**U.S. PATENT DOCUMENTS**

* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
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	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AR	Watanabe, et al., "Transparent Phase Shifting Mask"; IEDM Technical Digest. International Electron Devices Meeting 1990, pp. 821-824.
AS	Terasawa, et al., "Imaging Characteristics of Multi-Phase-Shifting and Halftone Phase-Shifting Masks." Japanese Journal of Applied Physics, Vol. 30, No. 11B (1991), pp. 2991-2997.
AT	

EXAMINER

DATE CONSIDERED

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT N. HASEGAWA et al				
				FILING DATE 02/13/04		GROUP 1756		
U.S. PATENT DOCUMENTS								
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)		
AR	AA	5,429,897	07/04/95	Yoshioka et al				
	AB	5,589,305	12/31/96	Tomofuji et al				
	AC	5,472,813	12/1995	Nakagawa et al				
	AD	5,574,492	11/1996	Suzuki				
	AE	4,360,586	11/23/82	Flanders et al				
	AF	4,890,309	12/26/89	Smith et al				
	AG	5,328,807	07/12/94	Tanaka et al				
	AH	5,364,716	11/15/94	Nakagawa et al				
	AI	5,837,405	11/17/98	Tomofuji et al				
	AJ	5,660,956	08/26/97	Tomofuji et al				
	AK	5,595,844	01/21/97	Tomofuji et al				
FOREIGN PATENT DOCUMENTS								
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO		
AR	AL	62-50811	10/27/87	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM	4-136854	05/11/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN	144453	06/19/91	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AO	269532	12/02/91	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AP	1750/95	02/28/95	Korea			<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
AR	AS	Flanders et al, "Spatial period division - A new technique for exposing submicrometer-line width periodic and quasiperiodic patterns", JOURNAL OF VACUUM SCIENCE TECHNOLOGY, 16(6), Nov/Dec 1979, pp. 1949-1952						
	AT							
EXAMINER A. Dosasa				DATE CONSIDERED 8-5-05				

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	AA						
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FOREIGN PATENT DOCUMENTS							
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AL	4-223464	08/13/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
AM	4-204653	07/27/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
AN						<input type="checkbox"/>	<input type="checkbox"/>
AO						<input type="checkbox"/>	<input type="checkbox"/>
AP						<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
AR							
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EXAMINER <i>A. Zwass</i>				DATE CONSIDERED <i>8-5-05</i>			
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